OPERATION OF DIAMOND LIGHT SOURCE XBPMS WITH ZERO BIAS

Chris Bloomer, Guenther Rehm,

Diamond Light Source, Harwell Science and Innovation Campus, Didcot, Oxon OX11 0DE

Abstract

Tungsten blade X-ray Beam Position Monitors (XBPMs) have been used at Diamond Light Source since 2007, however a long-standing problem with these devices has been the growth of leakage current through the ceramic insulation



within the XBPMs over time, often becoming greater than 10% of the signal current after a few years of operation. The growth of these leakage currents has been found to be exacerbated by the application of a negative bias (-70V) to the tungsten blades, a bias suggested by the original designers of our XBPMs for optimum position sensitivity. This bias is applied in order to accelerate free electrons away from the surface of the blades and to prevent cross-talk, however, we have found that the operation of the XBPMs without bias has negligible impact on our measurements. Removal of the bias has been found to prevent the growth of leakage currents over time, and can also significantly reduce the cost of our signal acquisition by removing the need for a low-current amplifier with a bias supply.



Leakage currents seen on one of our XBPMs when a -70V bias is applied. *This represents >10% of the signal current seen with beam.*

currents at 300mA for various ID gaps and



Results from a 2D stepper motor scan of the I24 XBPM-01 with, and without, bias. The recorded Δ/Σ position measurements are shown, with points evenly spaced: each represents a 200µm stepper-motor movement.

It was found that the linearity of the XBPM position measurements remained, and that the scale factors were improved by the removal of the bias. This has the unanticipated effect of making the position measurement more sensitive.

For more information please visit www.diamond.ac.uk or contact Chris Bloomer at chris.bloomer@diamond.ac.uk

